

Search Notes**Application/Control No.**

10/042,762

Examiner

Hanh Nguyen

Applicant(s)/Patent under Reexamination

LI ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
375	240.11	10/22/2007	HN
	240.1		
	240.15		
	240.21		
	240.12		
	240.08		
	240		
370	235		
	229		
	230		
	465		
	238		
	485		
	486	10/22/2007	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
370	235	10/22/2007	HN
	486		
	465		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/22/2007	HN